



# **HY11P32**

## **Datasheet**

**8-Bit RISC-Like Mixed Signal Microcontroller**  
**Embedded 4x12 LCD Driver**  
**18-Bit  $\Sigma$ ADC**

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### 1. Features

- 8-bit RISC, 46 instructions included.
- Operating voltage range: 2.2V to 3.6V, operation temperature range: -40°C~85°C.
- External Crystal Oscillator and Internal High Precision RC Oscillator, 6 CPU clock rates enable users to have the most power-saving plan.
  - Active Mode 300uA@2MHz
  - Standby Mode 3uA@28KHz
  - Sleep Mode 1uA
- 2K Word OTP (One Time Programmable) Type Program Memory, 128 Byte Data Memory
- Brownout detector and Watch dog Timer, prevents CPU from Crash.
- 18-bit fully differential input Sigma-Delta Analog-to-Digital Converter (A/D)
  - Built-in PGA (Programmable Gain Amplifier) 1/4x · 1/2x · 1x. ...128x · 10 input signal gain selection.
  - Built-in Input zero point adjustment can increase measurement range according to different application.
- 1.0V internal analog circuit common ground that equips with Push-Pull drive ability to provide sensor driving voltage.
- LVD low voltage detection function has 14 steps of voltage detection configuration and external input voltage detection function.
- Analog voltage source, VDDA equips with 10mA low dropout regulator function
- 4x12 LCD Driver
  - 1/4 Duty, 1/3 Bias
  - Built-in Charge Pump regulated circuit, providing 4 LCD Bias voltage
- 8-bit Timer A
- Built-in EPROM (BIE)
- Support 6 stack level

## 2. Pin Definition

### 2.1 PIN Diagram LQFP44

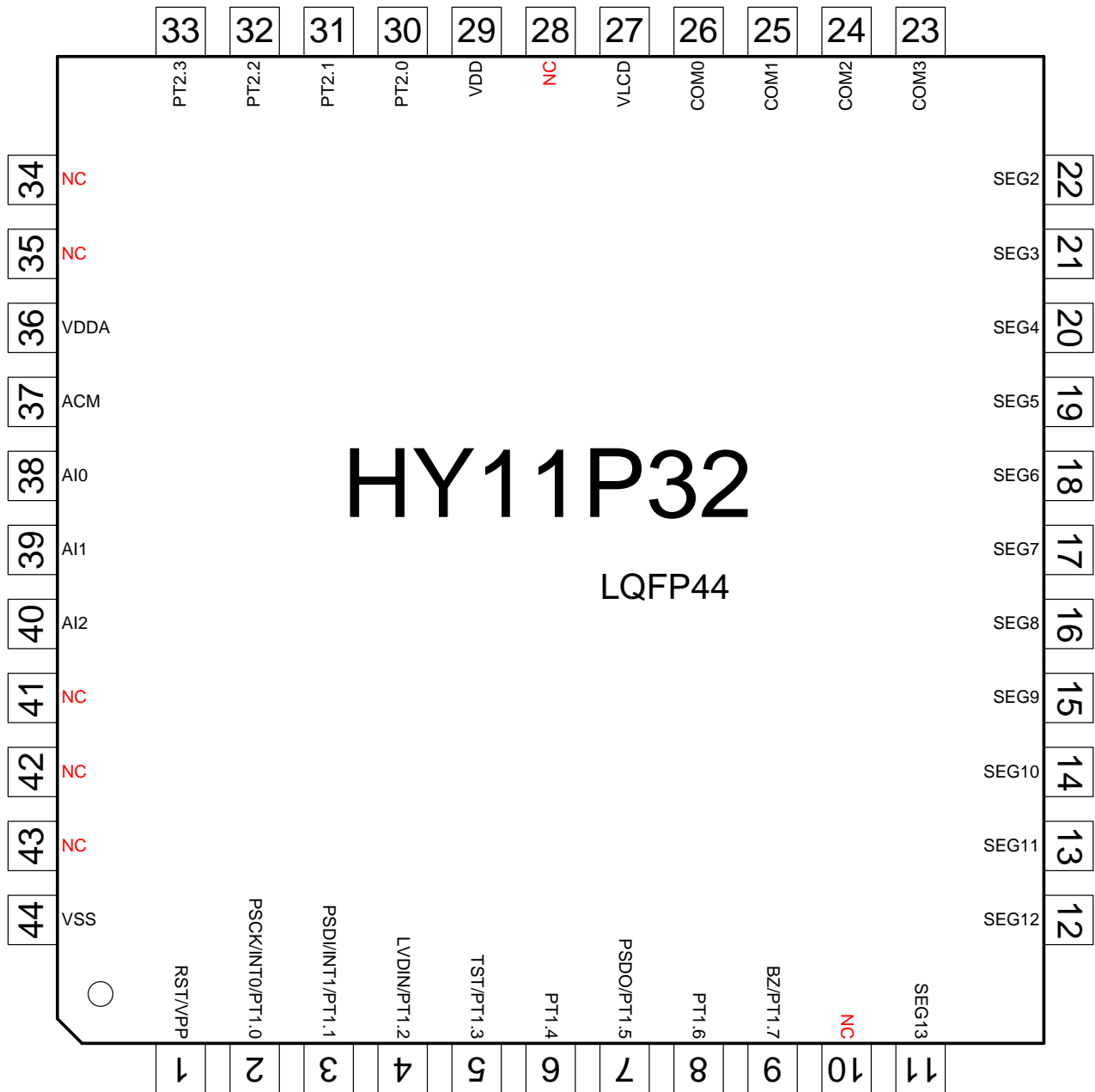


Figure 2-1 HY11P32 LQFP44 Pin Diagram

Note 1 : VPP and RST use the same pin. Input voltage cannot exceed 5.8V when not programming EPROM.

Note 2 : TST and PT1.3 use the same pin. Input voltage cannot exceed Vdd+0.3V while operating.

Note 3 : If PT1.3 is not configured as external pin button, it can help to enhance the anti-interference ability.

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## 2.2 PIN Diagram LQFP48

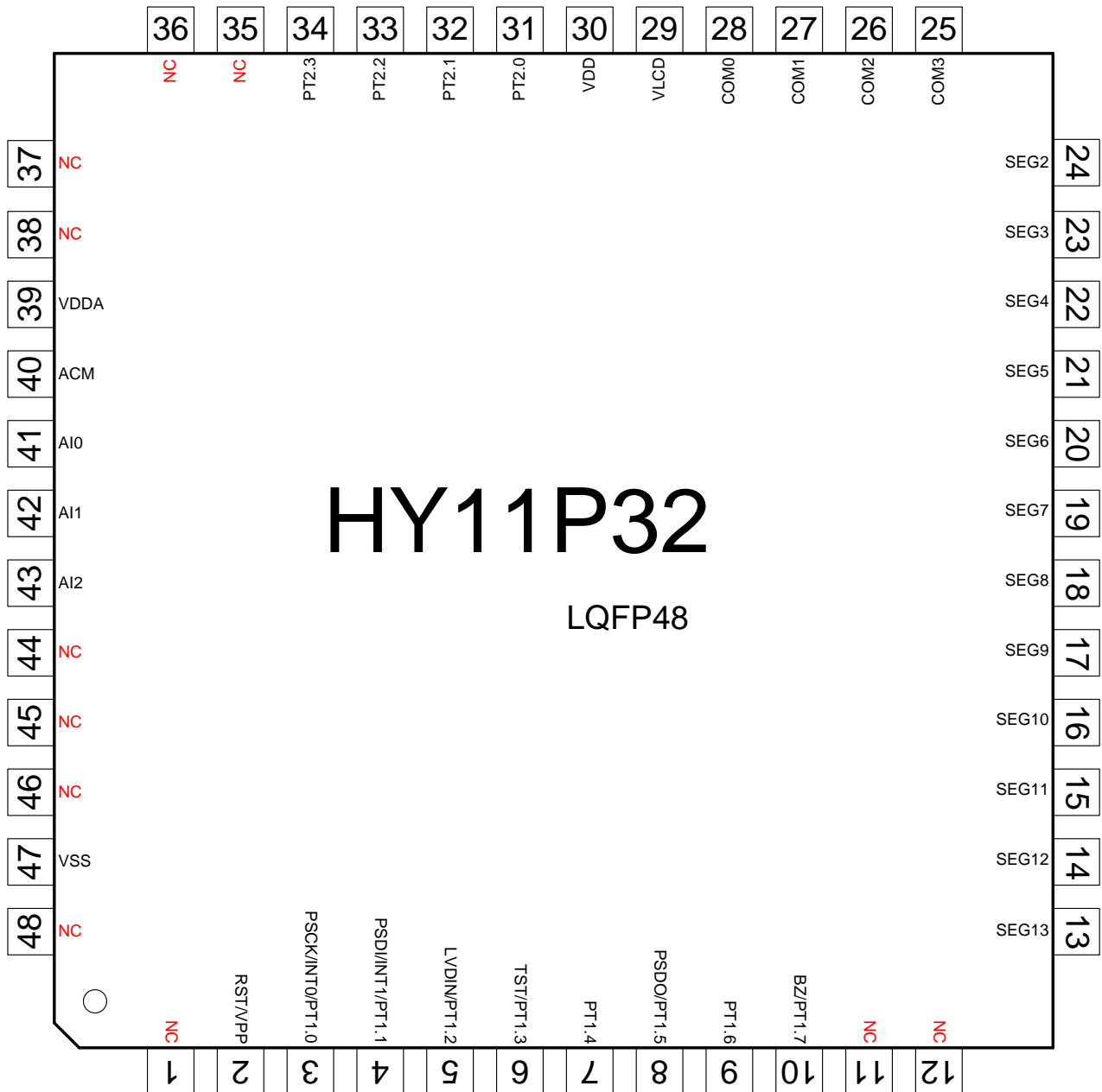


Figure 2-1 HY11P32 LQFP48 Pin Diagram

Note 1 : VPP and RST use the same pin. Input voltage cannot exceed 5.8V when not programming EPROM.

Note 2 : TST and PT1.3 use the same pin. Input voltage cannot exceed Vdd+0.3V while operating.

Note 3 : If PT1.3 is not configured as external pin button, it can help to enhance the anti-interference ability.

## 2.3 LQFP44 Pinout I/O Description

"I/O" input/output, "I" input, "O" output, "S" Smith Trigger, "C" CMOS features compatible input/output, "P" power supply, "A" analog channel

NO.	Pin Name	Pin Characteristic		Description
		Pin Type	Buffer Type	
1	RST	I	S	Reset IC
	VPP	P	P	EPROM programming voltage input
2	PT1.0	I	S	Digital input
	INT0	I	S	Interrupt input INT0
	PSCK	I	S	OTP programming interface SCK
3	PT1.1	I	S	Digital input
	INT1	I	S	Interrupt input INT0
	PSDI	I	S	OTP programming interface SDI
4	PT1.2	I	S	Digital input
	LVDIN	A	A	LVD external signal input pin
5	PT1.3	I	S	Digital input
	TST	I	S	Test Mode input pin (invalid)
6	PT1.4	I/O	S	Digital I/O
7	PT1.5	I/O	S	Digital I/O
	PSDO	O	C	OTP programming interface SDO
8	PT1.6	I/O	S	Digital I/O
9	PT1.7	I/O	S	Digital I/O
	BZ	O	C	Buzzer output
10	NC	-	-	Unused
11	SEG13	O	A	Segment output for LCD
12	SEG12	O	A	Segment output for LCD
13	SEG11	O	A	Segment output for LCD
14	SEG10	O	A	Segment output for LCD
15	SEG9	O	A	Segment output for LCD
16	SEG8	O	A	Segment output for LCD

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17	SEG7	O	A	Segment output for LCD
18	SEG6	O	A	Segment output for LCD
19	SEG5	O	A	Segment output for LCD
20	SEG4	O	A	Segment output for LCD
21	SEG3	O	A	Segment output for LCD
22	SEG2	O	A	Segment output for LCD
23	COM3	O	A	COM segment output for LDO
24	COM2	O	A	COM segment output for LDO
25	COM1	O	A	COM segment output for LDO
26	COM0	O	A	COM segment output for LDO
27	VLCD	P	P	Power supply for LCD
28	NC	-	-	Unused
29	VDD	P	P	Power supply for IC operation
30	PT2.0	I/O	S	Digital I/O
31	PT2.1	I/O	S	Digital I/O
32	PT2.2	I/O	C	Digital I/O
33	PT2.3	I/O	S	Digital I/O
34	NC	-	-	Unused
35	NC	-	-	Unused
36	VDDA	P	P	Regulator output, analog circuit voltage source
37	ACM	P	P	Internal analog circuit common ground pin
38	AI0	A	A	Analog input channel
39	AI1	A	A	Analog input channel
40	AI2	A	A	Analog input channel
41	NC	-	-	Unused
42	NC	-	-	Unused
43	NC	-	-	Unused
44	VSS	P	P	Grounding pin for IC operation voltage

Table 2-1 Pin Definition and Function Description



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## 3. Application Circuit

### 3.1 Bridge Sensor I

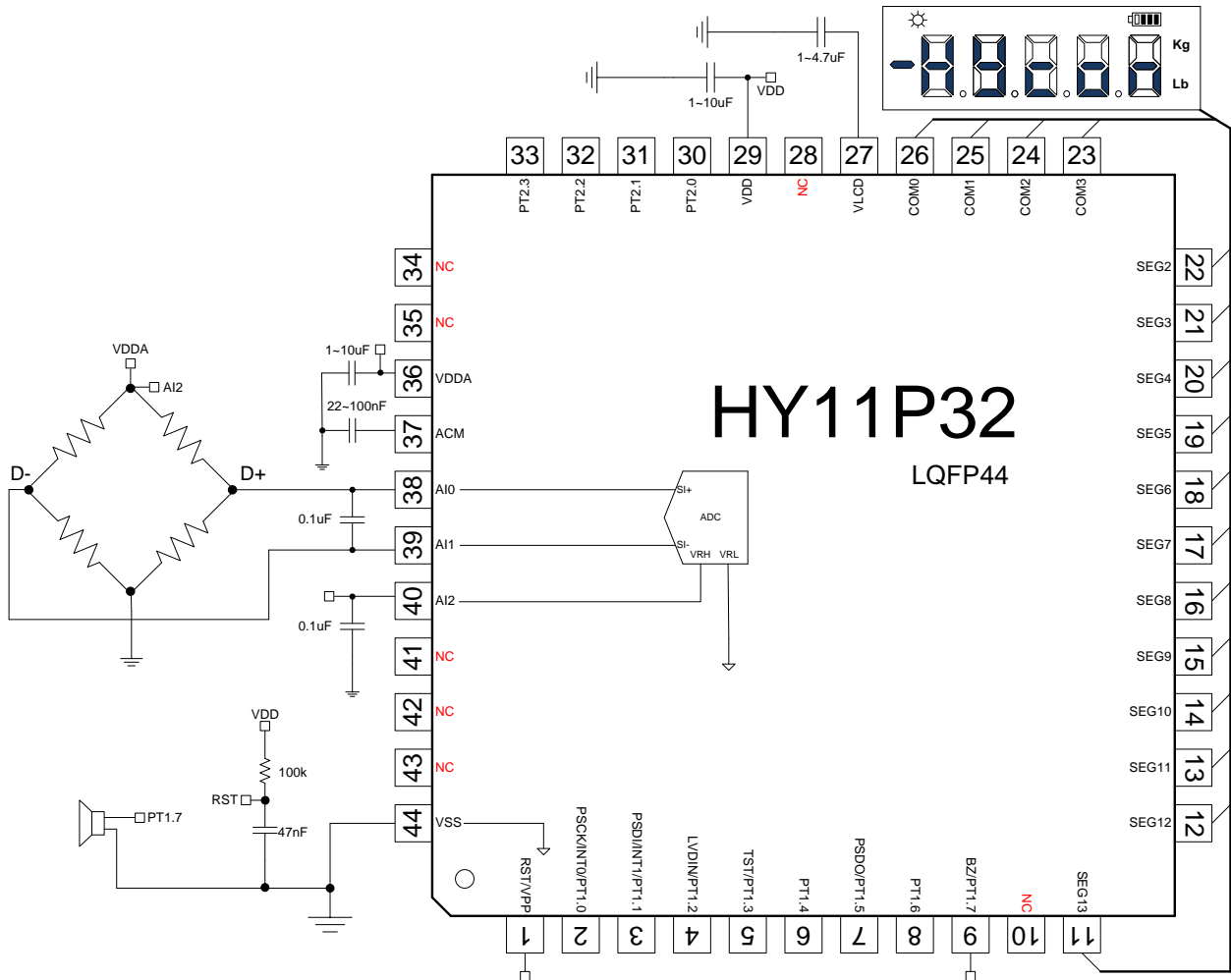


Figure 3-1 Bridge Sensor Application Circuit

Note 1 : DCSET[2:0] can conduct bias adjustment of Load Cell zero point voltage address

## 4. Function Outline

### 4.1 Internal Block Diagram

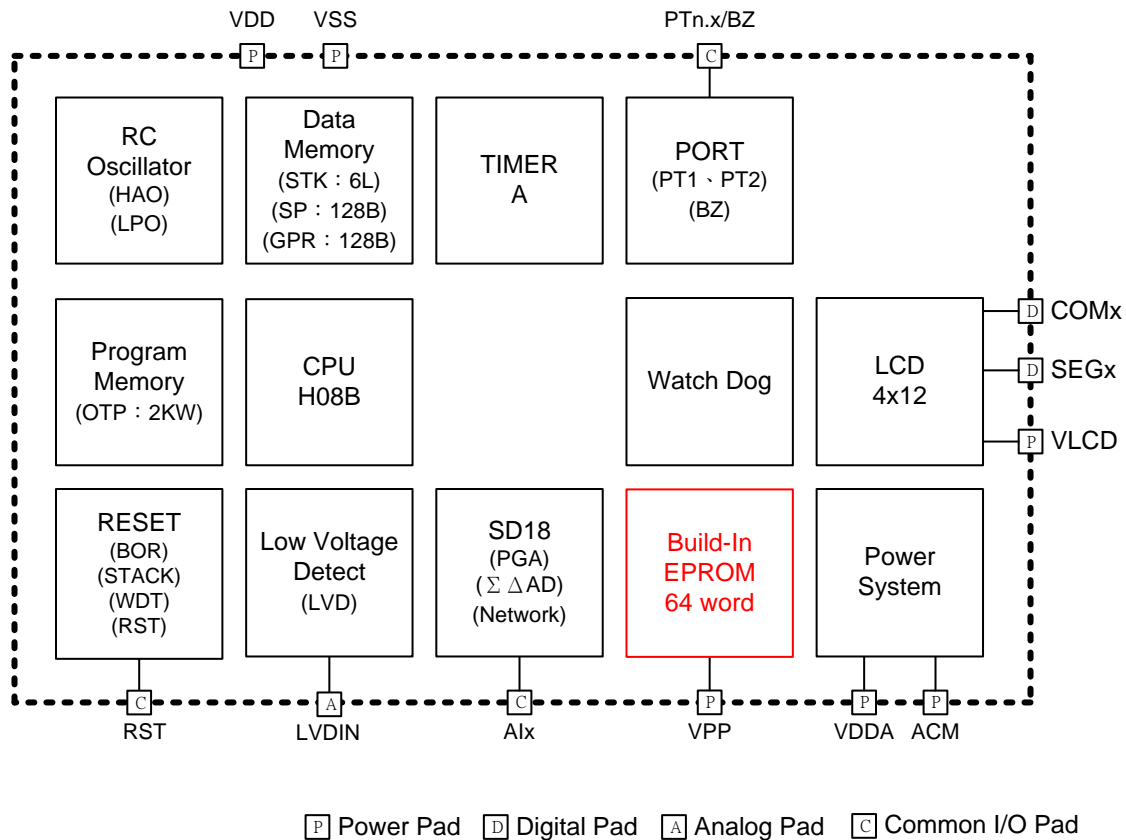


Figure 4-1 HY11P32 Internal Block Diagram

### 4.2 Related Description and Supporting Documents

#### IC Function Related Operating Instruction

DS-HY11P32-Vxx	HY11P32 Datasheet
UG-HY11S14-Vxx	HY11Pxx Series Users' Manual
APD-CORE003-Vxx	H08B Instruction Description

#### Development Tool Related Operating Instruction

APD-HYIDE006-Vxx	HY11xxx Series Development Tool Software Instruction Manual
APD-HYIDE005-Vxx	HY11xxx Series Development Tool Hardware Instruction Manual
APD-OTP001-Vxx	OTP Products Programming Pin Manual Product Production Related Operating Instruction
APD-HYIDE004-Vxx	HY1xxxx Series Production Line Specialized Programmer Manual
BDI-HY11P32-Vxx	HY11P32 Individual Product Die Bonding Information

## 4.3 SD18 Network

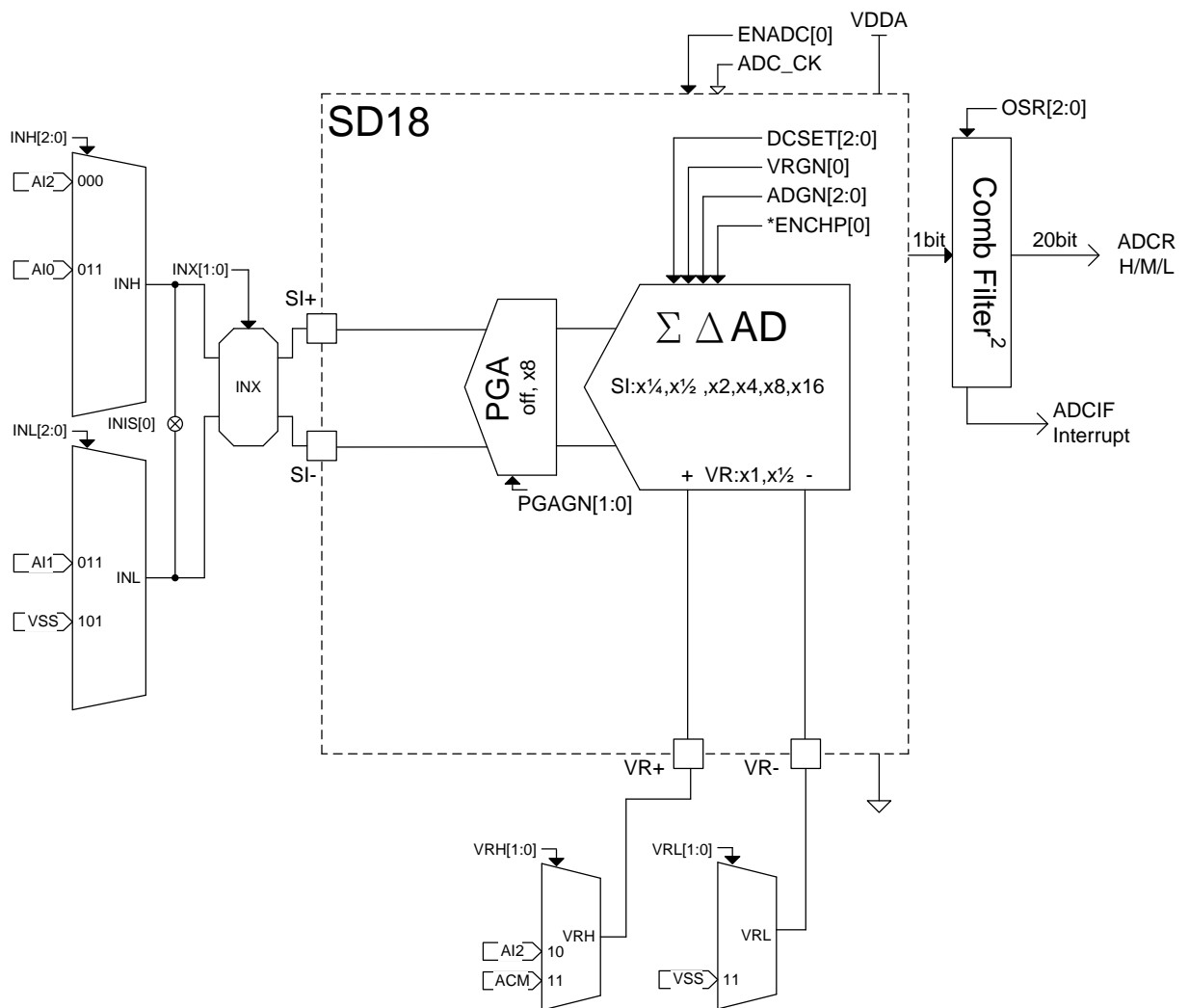


Figure 4-2 SD18 Network

### 5. Register List

Register File Summary for H08B															
"-" no use, "r" read/write, "w" write, "r" read, "r0" only read 0, "r1" only read 1, "w0" only write 0, "w1" only write 1 "-" unimplemented bit, "x" unknown, "u" unchanged, "d" depends on condition															
Address	File Name	Bit7	Bit6	Bit5	Bit4	Bit3	Bit2	Bit1	Bit0	A-RESET	I-RESET	R/W			
00H	INDF0	Contents of FSR0 to address data memory -value of FSR0 not changed									N/A	N/A	*****		
10H	FSROL	Indirect Data Memory Address Pointer 0 Low Byte,FSR0[7:0]									xxxx xxxx	uuuu uuuu	*****		
18H	STKPTR	STKFL	STKUN	STKOV	STKPR[2:0]							000..000	000..000	r,rw0,rw0,-,r,r,r	
1AH	PCLATH						PC[10]	PC[9]	PC[8]				....000	....000	*****
1BH	PCLATL	PC Low Byte for PC<7:0>									0000 0000	0000 0000	*****		
1CH	BIECTRL					VPP_HIGH	BIEWR			BIERD	1000 d000	1000 d000	.....r0,r		
1EH	BIEPTL	0	0	BIE_ADDR[5:0]							0000 0000	0000 0000	w0,w0,*****		
1FH	BIEDH	BIE_DATA[15:8]									xxxx xxxx	xxxx xxxx	*****		
20H	BIEDL	BIE_DATA[7:0]									xxxx xxxx	xxxx xxxx	*****		
23H	INTE1	GIE	ADCIE				TMAIE	WDTIE	E1IE	E0IE	0000 0000	0000 0000	*r0,r0,*****		
26H	INTF1				ADCIF				TMAIF	WDTIF	E1IF	E0IF	.000 0000	.000 0000	..r0,r0,*****
29H	WREG	Working Register									xxxx xxxx	uuuu uuuu	*****		
2BH	STATUS					C				Z	xxxx xxxx	xxxx xxxx	.....		
2CH	Pstatus	PD	TO	IDLEB	BOR	SKERR						000d xxxx	000d xxxx	rw0,rw0,rw0,rw0,x,x,x	
2DH	LVDCN	LVDFG		LVD	LVDON	VLDX[3:0]					x000 0000	x000 0000	x,r,r,r,*****		
30H	PWRCN	ENVDDA	VDDAX[1:0]=11		ENACM						0xx0 xxxx	0xx0 xxxx	..r,r,r,x,x,x,x		
31H	MCKCN1	ADCS[2:0]		ADCK				ENXT=0	ENHAO	0000 0001	0000 0001	*****r0,r0,r0,*			
32H	MCKCN2			LSCK=0	HSCK=0	HSS[1:0]=00		CPUCK[1:0]				.00 0000	.00 0000	r0,r0,r0,r0,r0,r0,*	
33H	MCKCN3	LCDS[2:0]			PERCK	BZS[2:0]						000..0000	000..0000	*****r0,*****	
39H	ADCRH	ADC conversion memory HighByte									xxxx xxxx	uuuu uuuu	r,r,r,r,r,r,r		
3AH	ADCRM	ADC conversion memory Middle Byte									xxxx xxxx	uuuu uuuu	r,r,r,r,r,r,r		
3BH	ADCRL	ADC conversion memory Low Byte									xxxx xxxx	uuuu uuuu	r,r,r,r,r0,r0,r0		
3CH	ADCCN1	ENADC	ENCHP		PGAGN[1:0]=00 or 11	ADGN[2:0]				0000 0000	0000 0000	*r0,*****			
3DH	ADCCN2			INBUF=0	VRBUF=0	VREGN	DCSET[2:0]				0000 0000	0000 0000	r0,r0,r0,r0,*****		
3EH	ADCCN3	OSR[2:0]									0000 0000	0000 0000	*****r0,r0,r0,r0		
3FH	AINET1	INH[2:0]=XX0 or XX1(AI2 or AI0)			INL[2:0]=0XX or 1XX(AI1 or VSS)			INIS					xx00 xx0x	xx00 xx0x	x,x,*,*,x,x,*,x
40H	AINET2	VRL[1:0]=X0 or X1(AI2 or ACM)			INX[1:0]		VRL[1:0]=11(VSS)				xx00 0xxx	xx00 0xxx	x,x,*,*,*,x,x,x		
41H	TMACN	ENTMA	TMACK	TMAS[1:0]	ENWDT	WDTS[2:0]				0000 0000	0000 0000	*****w1,*****			
42H	TMAR	TimerA data register									xxxx xxxx	uuuu uuuu	r,r,r,r,r,r,r		
52H	LCDCN1	ENLCD	LC DPR	VLCDX[1:0]		LCDBF	LCDBI[1:0]=10				0000 0xxx	0000 0xxx	.....*,x,x,x		
53H	LCDCN2	LCDBL	LC DMX[1:0]=11								0xxx xxxx	0xxx xxxx	*,x,x,x,x,x,x,x		
54H	LCD0	Segment SEG2@[3:0] and SEG3@[7:4] data register of LCD0									xxxx xxxx	uuuu uuuu	*****		
55H	LCD1	Segment SEG4@[3:0] and SEG5@[7:4] data register of LCD1									xxxx xxxx	uuuu uuuu	*****		
56H	LCD2	Segment SEG6@[3:0] and SEG7@[7:4] data register of LCD2									xxxx xxxx	uuuu uuuu	*****		
57H	LCD3	Segment SEG8@[3:0] and SEG9@[7:4] data register of LCD3									xxxx xxxx	uuuu uuuu	*****		
58H	LCD4	Segment SEG10@[3:0] and SEG11@[7:4] data register of LCD4									xxxx xxxx	uuuu uuuu	*****		
59H	LCD5	Segment SEG12@[3:0] and SEG13@[7:4] data register of LCD5									xxxx xxxx	uuuu uuuu	*****		
6DH	PT1	PT1.7	PT1.6	PT1.5	PT1.4	PT1.3	PT1.2	PT1.1	PT1.0	xxxx xxxx	uuuu uuuu	.....r,r,r,r			
6EH	TRISC1	TC1.7	TC1.6	TC1.5	TC1.4					0000 0000	0000 0000	*****r0,r0,r0,r0			
70H	PT1PU	PU1.7	PU1.6	PU1.5	PU1.4	PU1.3	PU1.2	PU1.1	PU1.0	0000 0000	0000 0000	*****			
71H	PT1M1						INTEG1[1:0]		INTEG0[1:0]		0000 0000	0000 0000	r0,r0,r0,r0,*****		
72H	PT1M2	PM1.7[0]										0000 0000	0000 0000	r0,r0,r0,r0,r0,r0,r0	
74H	PT2					PT2.3	PT2.2	PT2.1	PT2.0	....xxxx	....uuuu	x,x,x,x,*****			
75H	TRISC2					TC2.3	TC2.2	TC2.1	TC2.0	....0000	....0000	x,x,x,x,*****			
77H	PT2PU					PU2.3	PU2.2	PU2.1	PU2.0	....0000	....0000	x,x,x,x,*****			
80H ~ FFH	GENERAL PURPOSE REGISTER @ 128Byte										xxxx xxxx	uuuu uuuu	*****		

Figure 5-1 HY11P32 Register List

## 6. Electrical Characteristics

Absolute maximum ratings over operating free-air temperature (unless otherwise noted)

Voltage applied at $V_{DD}$ to $V_{SS}$ .....	-0.2 V to 4.0 V
Voltage applied to any pin (see Note 1) .....	-0.2 V to $V_{DD} + 0.3$ V
Voltage applied to RST/VPP pin .....	-0.2 V to 6.9 V
Voltage applied to TST/PT1.3 pin (see Note 1) .....	-0.2 V to $V_{DD} + 1$ V
Diode current at any device terminal .....	$\pm 2$ mA
Storage temperature, Tstg: (unprogrammed device) .....	-55°C to 150°C
(programmed device) .....	-40°C to 85°C
Total power dissipation.....	0.5w
Maximum output current sink by any PORT1 to PORT2 I/O pin.....	.25mA

### 6.1 Recommended Operating Conditions

$T_A = -40^\circ\text{C} \sim 85^\circ\text{C}$ , unless otherwise noted

Sym.	Parameter	Test Conditions	Min.	Typ.	Max.	unit
$V_{DD}$	Supply Voltage	All digital peripherals and CPU	2.2		3.6	V
		Analog peripherals	2.4		3.6	
$V_{SS}$	Supply Voltage		0		0	

## 6.2 Internal RC Oscillator

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}$ , unless otherwise noted

Sym.	Parameter	Test Conditions	Min.	Typ.	Max.	unit
HAO	High Speed Oscillator frequency	ENHAO[0]=1	1.6	2.0	2.4	MHz
LPO	Low Power Oscillator frequency	$V_{DD}$ supply voltage be enable LPO	22	28	35	KHz

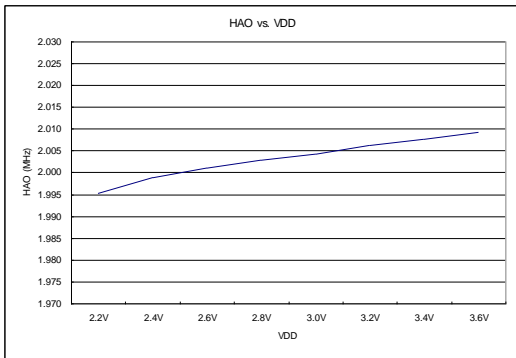


Figure 6.2-1 HAO vs. VDD

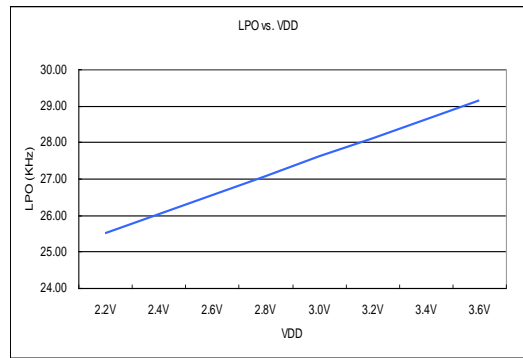


Figure 6.2-2 LPO vs. VDD

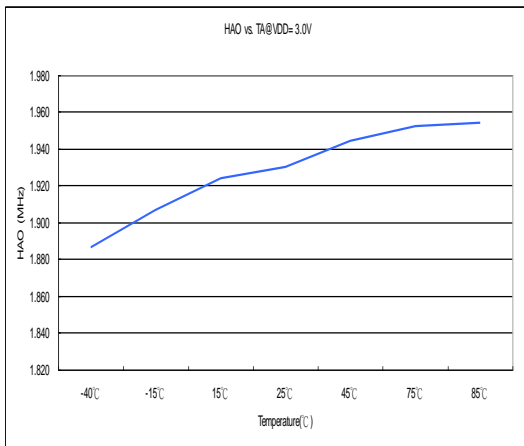


Figure 6.2-3 HAO vs. Temperature

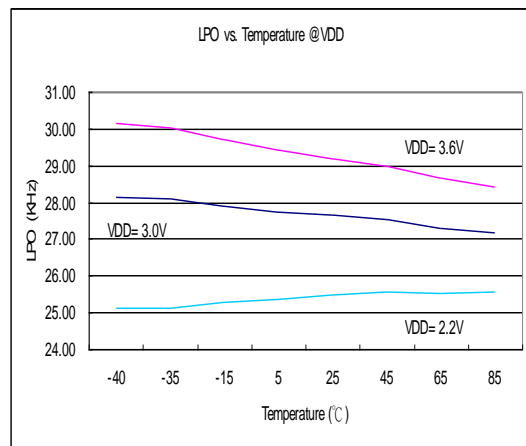


Figure 6.2-4 LPO vs. Temperature

### 6.3 Supply Current into VDD Excluding Peripherals Current

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}, \text{OSC\_LPO} = 28\text{KHz}$ , unless otherwise noted

Sym.	Parameter	Test Conditions	Min.	Typ.	Max.	unit
I <sub>AM2</sub>	Active mode 2	OSC_CY = off, OSC_HAO = 2MHz, CPU_CK = 2MHz		0.28	0.55	mA
I <sub>AM3</sub>	Active mode 3	OSC_CY = off, OSC_HAO = 2MHz, CPU_CK = 1MHz		0.165	0.3	mA
I <sub>LP2</sub>	Low Power 2	OSC_CY = off, OSC_HAO = off, CPU_CK = LPO, Idle state		1.65	3	uA
I <sub>LP3</sub>	Low Power 3	OSC_CY = off, OSC_HAO = off, CPU_CK = off, Sleep state		0.65	1.2	uA

OSC\_HAO : Internal High Accuracy Oscillator frequency.

CPU\_CK : CPU core work frequency.

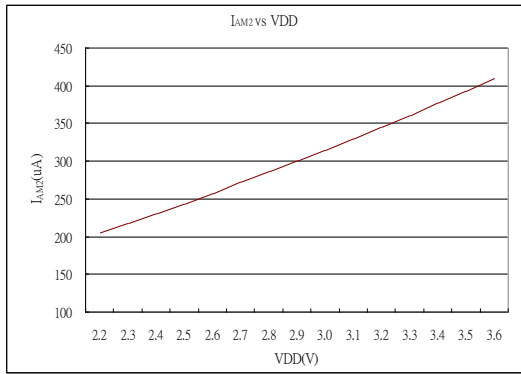


Figure 6.3-1 I<sub>AM2</sub> vs. VDD

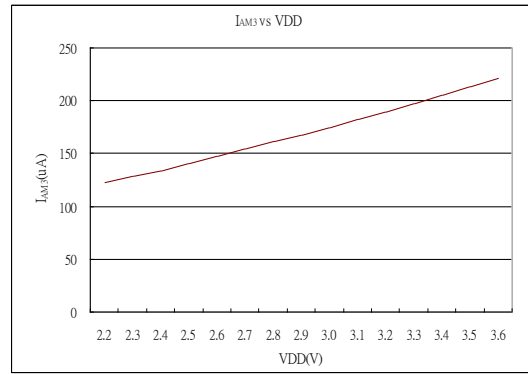


Figure 6.3-2 I<sub>AM3</sub> vs. VDD

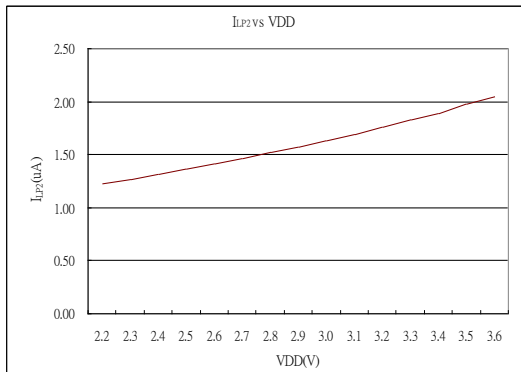


Figure 6.3-3 I<sub>LP2</sub> vs. VDD

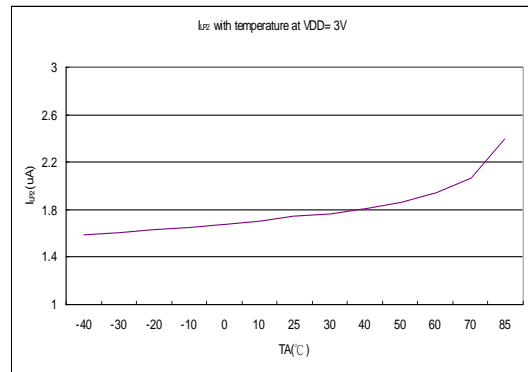


Figure 6.3-4 I<sub>LP2</sub> vs. Temperature

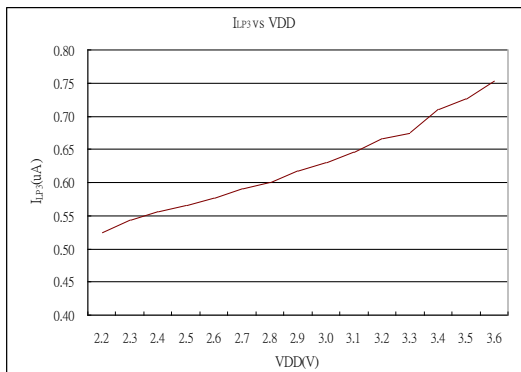


Figure 6.3-5 I<sub>LP3</sub> vs. VDD

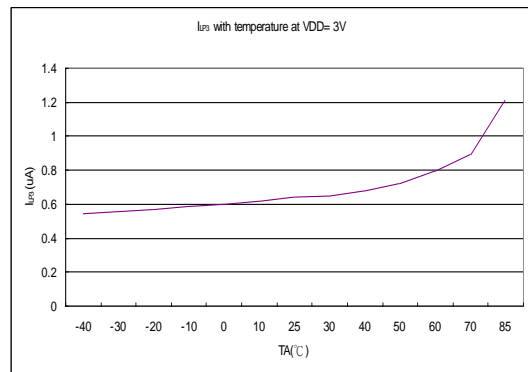


Figure 6.3-6 I<sub>LP3</sub> vs. Temperature

### 6.4 Port1~2

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}$ , unless otherwise noted

Sym.	Parameter	Test Conditions	Min.	Typ.	Max.	unit
<b>Input voltage and Schmitt trigger and leakage current and timing</b>						
$V_{IH}$	High-Level input voltage				2.1	V
$V_{IL}$	Low-Level input voltage		0.9			
$V_{hys}$	Input Voltage hysteresis( $V_{IH} - V_{IL}$ )			0.8		V
$I_{LKG}$	Leakage Current				0.1	$\mu\text{A}$
$R_{PU}$	Port pull high resistance			180		$\text{k}\Omega$
<b>Output voltage and current and frequency</b>						
$V_{OH}$	High-level output voltage	$I_{OH}=10\text{mA}$	$V_{DD} - 0.3$			V
$V_{OL}$	Low-level output voltage	$I_{OL}=-10\text{mA}$			$V_{SS} + 0.3$	

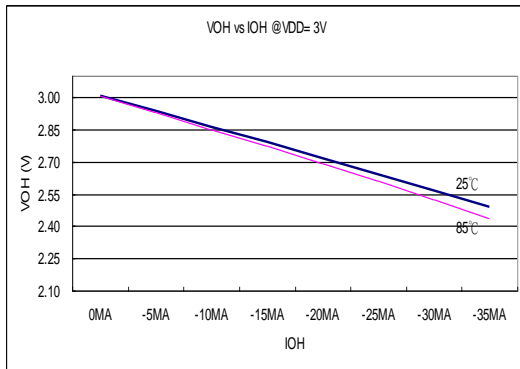


Figure 6.4-1  $V_{OH}$  vs.  $I_{OH}$  @  $V_{DD}=3.0\text{V}$

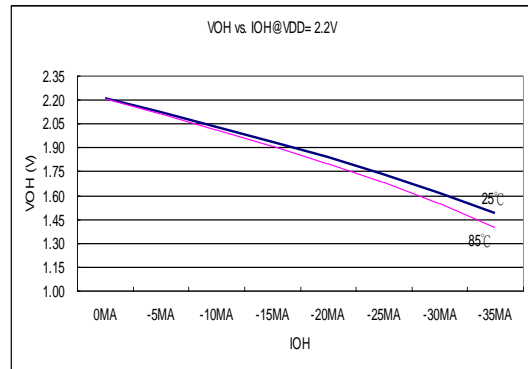


Figure 6.4-2  $V_{OH}$  vs.  $I_{OH}$  @  $V_{DD}=2.2\text{V}$

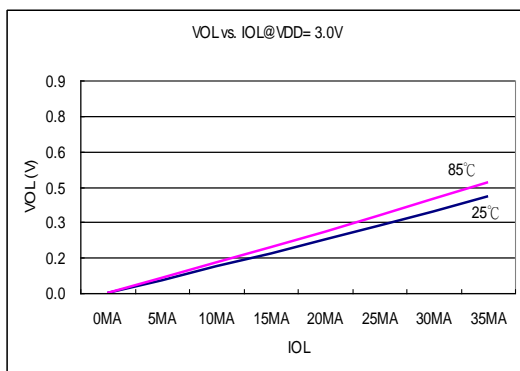


Figure 6.4-3  $V_{OL}$  vs.  $I_{OL}$  @  $V_{DD}=3.0\text{V}$

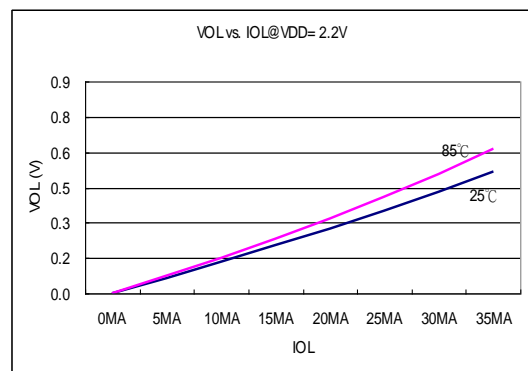


Figure 6.4-4  $V_{OL}$  vs.  $I_{OL}$  @  $V_{DD}=2.2\text{V}$



### 6.5 Reset (Brownout, External RST pin, Low Voltage Detect)

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}$ , unless otherwise noted

Sym.	Parameter	Test Conditions	Min.	Typ.	Max.	unit	
BOR	Pulse length needed to accepted reset internally, $t_{d-LVR}$		2			us	
	$V_{DD}$ Start Voltage to accepted reset internally (L→H), $V_{LVR}$		1.6	1.85	2.1	V	
	Hysteresis, $V_{HYS-LVR}$			70		mV	
RST	Pulse length needed as RST/VPP pin to accepted reset internally, $t_{d-RST}$		2			us	
	Input Voltage to accepted reset internally		0.9			V	
	Hysteresis, $V_{HYS-RST}$			0.8		V	
LVD	Operation current, $I_{LVD}$			10	15	uA	
	External input voltage to compare reference voltage			1.2		V	
	Compare reference voltage temperature drift	$T_A = -40^\circ\text{C} \sim 85^\circ\text{C}$		100		ppm/°C	
	Detect $V_{DD}$ voltage rang by user option, $V_{SVS} VLDx[3:0]=1110b$			3.3		V	
	Detect $V_{DD}$ voltage rang by user option, $V_{SVS} VLDx[3:0]=1101b$			3.2			
	Detect $V_{DD}$ voltage rang by user option, $V_{SVS} VLDx[3:0]=1100b$			3.1			
	Detect $V_{DD}$ voltage rang by user option, $V_{SVS} VLDx[3:0]=1011b$			3.0			
	Detect $V_{DD}$ voltage rang by user option, $V_{SVS} VLDx[3:0]=1010b$			2.9			
	Detect $V_{DD}$ voltage rang by user option, $V_{SVS} VLDx[3:0]=1001b$			2.8			
	Detect $V_{DD}$ voltage rang by user option, $V_{SVS} VLDx[3:0]=1000b$			2.7			
	Detect $V_{DD}$ voltage rang by user option, $V_{SVS} VLDx[3:0]=0111b$			2.6			
	Detect $V_{DD}$ voltage rang by user option, $V_{SVS} VLDx[3:0]=0110b$			2.5			
	Detect $V_{DD}$ voltage rang by user option, $V_{SVS} VLDx[3:0]=0101b$			2.4			
	Detect $V_{DD}$ voltage rang by user option, $V_{SVS} VLDx[3:0]=0100b$			2.3			
	Detect $V_{DD}$ voltage rang by user option, $V_{SVS} VLDx[3:0]=0011b$			2.2			
	Detect $V_{DD}$ voltage rang by user option, $V_{SVS} VLDx[3:0]=0010b$			2.1			
	Detect $V_{DD}$ voltage rang by user option, $V_{SVS} VLDx[3:0]=0001b$			2.0			
BOR : Brownout Reset LVR : Low Voltage Reset of BOR LVD : Low Voltage Detect RST : External Reset pin							

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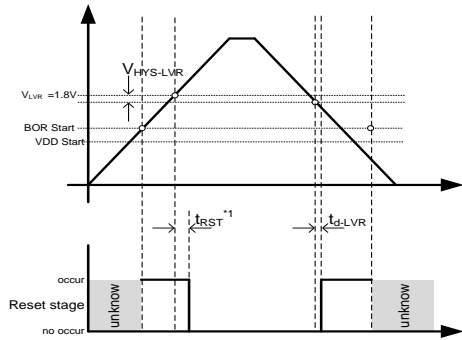


Figure 6.5-1 BOR reset diagram

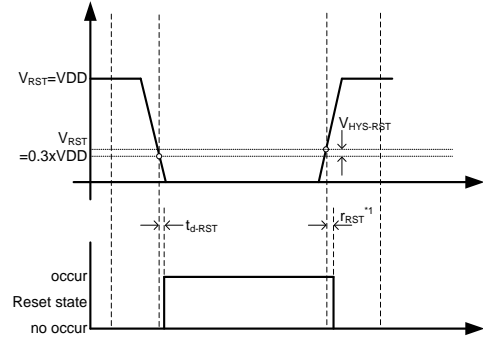


Figure 6.5-2 RST reset diagram

\*1  $t_{RST}$  : Please see BOR Introduce of HY11Pxx series User's Guide (UG-HY11S14-Vxx).

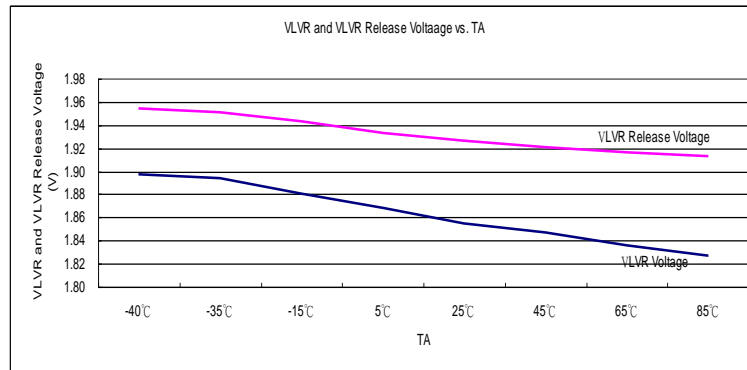


Figure 6.5-3 LVR vs. Temperature

### 6.6 Power System

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}$ , unless otherwise noted

Sym.	Parameter	Test Conditions		Min.	Typ.	Max.	unit
VDDA	VDDA operation current, $I_{VDDA}$	$I_L = 0\text{mA}$	VDDAX[1:0]=00b	22			$\mu\text{A}$
	Select VDDA output voltage	$I_L = 0.1\text{mA}$ , $V_{DD} \geq V_{DDA} + 0.2\text{V}$	VDDAX [1:0]=11b	2.4			V
	Dropout voltage	$I_L = 10\text{mA}$	VDDAX [1:0]=11b	180			mV
	Temperature drift	VDDAX [1:0]=11b	$T_A = -40^\circ\text{C} \sim 85^\circ\text{C}$	50			ppm/ $^\circ\text{C}$
	$V_{DD}$ Voltage drift	$I_L = 0.1\text{mA}$	$V_{DD} = 2.5\text{V} \sim 3.6\text{V}$	$\pm 0.2$			%/V
ACM	ACM operation current, $I_{ACM}$	$I_L = 0\text{mA}$		20			$\mu\text{A}$
	Output voltage, $V_{ACM}$	ENACM[0]=1	$I_L = 0\mu\text{A}$	1.0			V
	Output voltage with Load		$I_L = \pm 200\mu\text{A}$	0.98	1.02		$V_{ACM}$
	Temperature drift	ENACM[0]=1,	$T_A = -40^\circ\text{C} \sim 85^\circ\text{C}$	50			ppm/ $^\circ\text{C}$
	VDDA Voltage drift	$I_L = 10\mu\text{A}$		100			$\mu\text{V}/\text{V}$

VDDA : Adjust Voltage Regulator  
ACM : Analog Common Mode Voltage

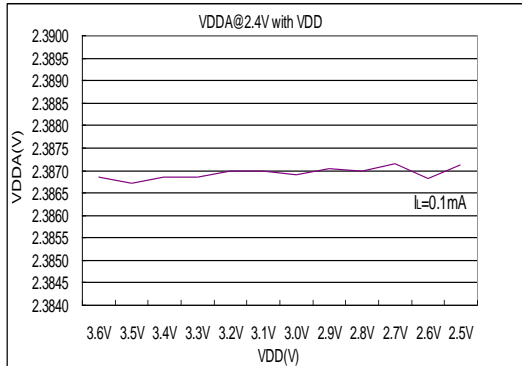


Figure 6.6-1 VDDA  $I_L=0.1\text{mA}$  vs. VDD

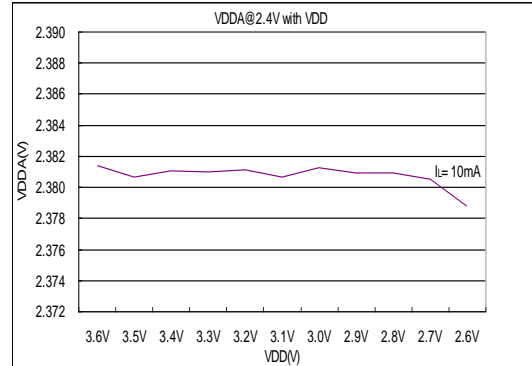


Figure 6.6-3 VDDA  $I_L=10\text{mA}$  vs. VDD

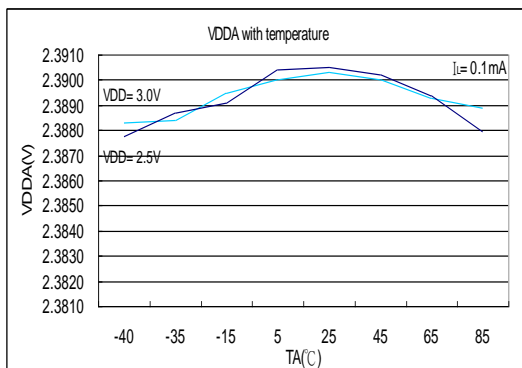


Figure 6.6-2 VDDA  $I_L=0.1\text{mA}$  vs. Temperature

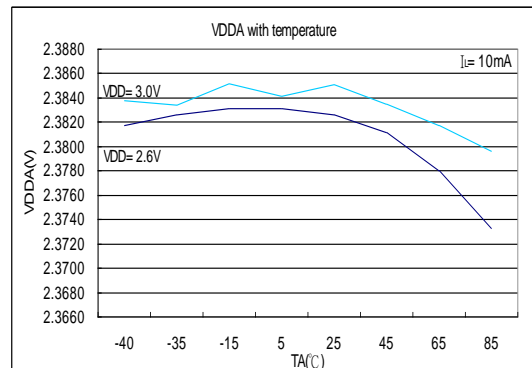


Figure 6.6-4 VDDA  $I_L=10\text{mA}$  vs. Temperature

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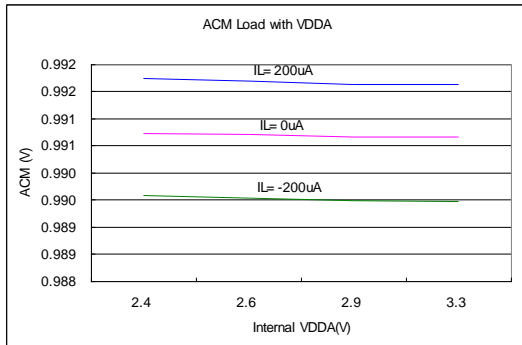


Figure 6.6-5 ACM Load vs. VDDA

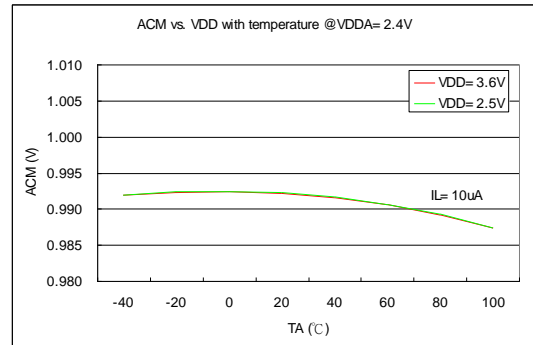


Figure 6.6-6 ACM vs. Temperature

### 6.7 LCD

$T_A = 25^\circ\text{C}$ ,  $V_{DD} = 3.0\text{V}$ ,  $C_{VLCD} = 4.7\mu\text{F}$ , unless otherwise noted.

Sym.	Parameter	Test Conditions	Min.	Typ.	Max.	unit	
$I_{LCD}$	Operation supply current without output buffer.(all segment turn on)	LCDPR[0]=1	$V_{DD} = 2.2\text{V}$	20		uA	
			$V_{DD} = 3.0\text{V}$				
VLCD	Supply Voltage at VLCD pin	LCDPR[0]=0	2.2		3.6	V	
	Embedded Charge Pump output voltage at VLCD pin	$V_{DD} = 2.2\text{V}$ , LCDPR[0]=1, $C_{VLCD} = 4.7\mu\text{F}$	VLCDX[1:0]=11b	2.295	2.55	2.805	V
			VLCDX[1:0]=10b	2.52	2.8	3.08	
			VLCDX[1:0]=01b	2.745	3.05	3.355	
VLCDX[1:0]=00b	2.97	3.3	3.63				
$Z_{LCD}$	Output impedance with LCD buffer	$f_{LCD} = 128\text{Hz}$ , VLCD=3.05V		10		k $\Omega$	

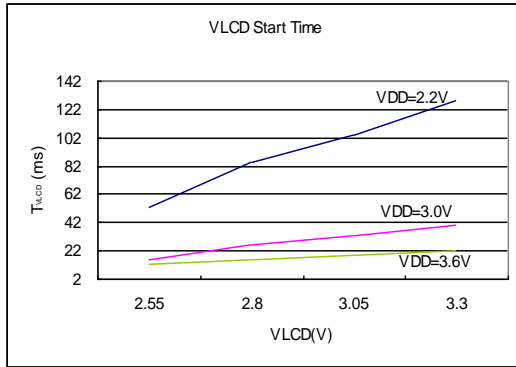


Figure 6.7-1 LCD Start Time

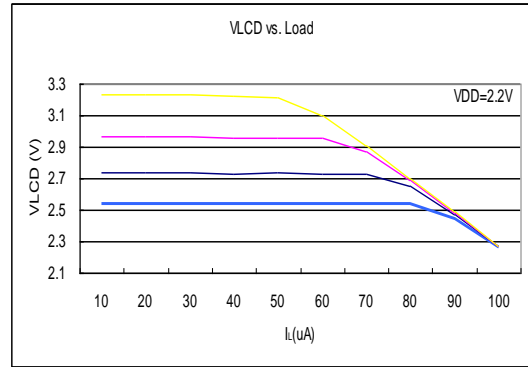


Figure 6.7-2 VLCD vs.  $I_L$  @ VDD=2.2V

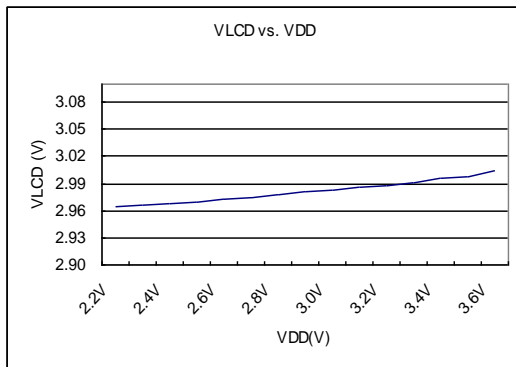


Figure 6.7-3 VLCD vs. VDD

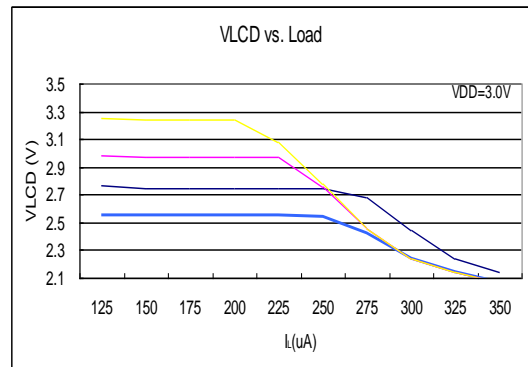


Figure 6.7-4 VLCD vs.  $I_L$  @ VDD=3.0V

### 6.8 SD18, Power Supply and Recommended Operating Conditions

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}, V_{DDA}=2.4\text{V}$ , unless otherwise noted

Sym.	Parameter	Test Conditions		Min.	Typ.	Max.	unit
$V_{SD18}$	Supply Voltage at VDDA	ENVDDA[0]=0		2.4		3.6	V
$f_{SD18}$	Modulator sample frequency, ADC_CK			25	250	300	KHz
	Over Sample Ratio, OSR			256		32768	
$I_{SD18}$	Operation supply current without PGA	ENADC[0]=1 INBUF[0]=0, VRBUF[0]=0	GAIN =4, ADC_CK=250KHz		120		$\mu\text{A}$

#### 6.8.1 PGA, Power Supply and Recommended Operating Conditions

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}, V_{DDA}=2.4\text{V}$ , unless otherwise noted

Sym.	Parameter	Test Conditions		Min.	Typ.	Max.	unit
$V_{PGA}$	Supply Voltage at VDDA	ENVDDA[0]=0		2.4		3.6	V
$I_{PGA}$	Operation supply current	PGAGN[1:0]=<11>			320		$\mu\text{A}$
$G_{PGA}$	Gain temperature drift	$T_A = -40^\circ\text{C} \sim 85^\circ\text{C}$	GAIN=128		15		ppm/ $^\circ\text{C}$

#### 6.8.2 SD18, Performance II ( $f_{SD18}=250\text{KHz}$ )

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}, V_{DDA}=2.9\text{V}, V_{VR}=1.0\text{V}, \text{GAIN}=1$  without PGA, unless otherwise noted

Sym.	Parameter	Test Conditions		Min.	Typ.	Max.	unit
INL	Integral Nonlinearity(INL)	$V_{DDA}=2.4\text{V}, V_{VR}=1.0\text{V}, \Delta\text{SI}=\pm 200\text{mV}$			$\pm 0.003$	$\pm 0.01$	%FSR
		$V_{DDA}=2.4\text{V}, V_{VR}=1.0\text{V}, \Delta\text{SI}=\pm 450\text{mV}$					
	No Missing Codes <sup>3</sup>	ADC_CK=250KHz, OSR[2:0]=010b		19			Bits
$G_{SD18}$	Temperature drift Gain 1~x16 (INBUF[0]=0b,)	INBUF[0]=0b, VRBUF[0]=0b	$T_A = -40^\circ\text{C} \sim 85^\circ\text{C}$		10		ppm/ $^\circ\text{C}$
Eos	Offset error of Full Scale Rang input voltage range with Chopper without PGA	$\Delta\text{AI}=0\text{V}$ $\Delta\text{VR}=0.9\text{V}$ DCSET[2:0]=<000> * $\Delta\text{AI}$ is external short	Gain=2			1	%FSR
			GAIN=1		2		$\mu\text{V}/^\circ\text{C}$
	GAIN=2		1				
	GAIN=4		0.5				
	GAIN=16		0.15				
$\text{CM}_{SD18}$	Common-mode rejection	$V_{CM}=0.7\text{V}$ to 1.7V, $V_{VR}=1.0\text{V}$ , without PGA	$V_{SI}=0\text{V}$ , GAIN=1		90		dB
		$V_{CM}=0.7\text{V}$ to 1.7V, $V_{VR}=1.0\text{V}$ , without PGA	$V_{SI}=0\text{V}$ , GAIN=16		75		

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PSRR	DC power supply rejection	VDDA=3.0V, $\Delta$ VDDA=±100mV, VVR=1.0V, VSI=1.2V, VSI=1.2V,	GAIN=1	75	dB
			PGA=off		
			GAIN=16		
			PGA=8		

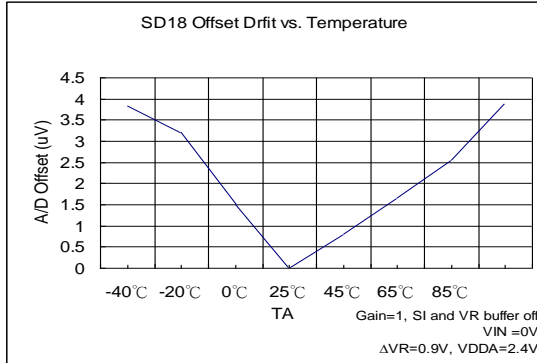


Figure 6.8-1(a) SD18 Offset Temperature Drift

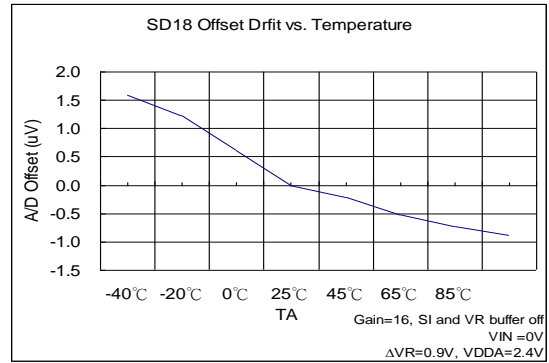


Figure 6.8-1(b) SD18 Offset Temperature Drift

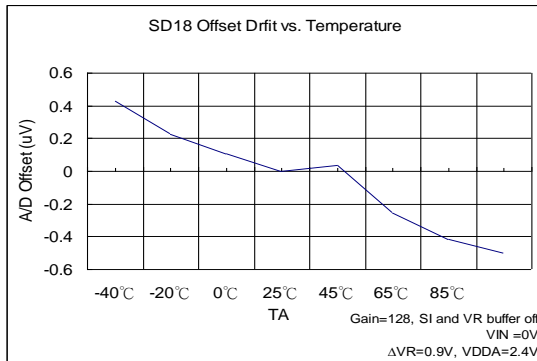


Figure 6.8-1(c) SD18 Offset Temperature Drift

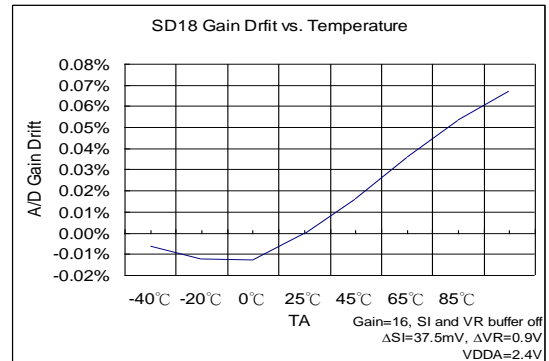


Figure 6.8-2(a) SD18 Gain Drift with Temperature

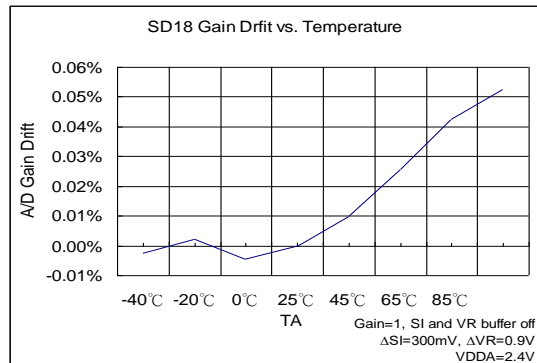


Figure 6.8-2(b) SD18 Gain Drift with Temperature

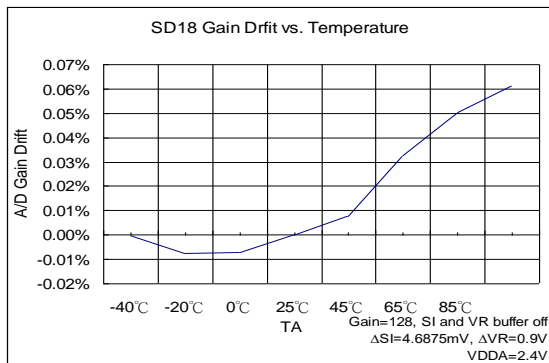


Figure 6.8-2(c) SD18 Gain Drift with Temperature

### 6.8.3 SD18 Noise Performance

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}, V_{DDA} = 2.4\text{V}$ , unless otherwise noted

HY11P32 provides important input noise specification that aims at SD18. Table6.8-3(a) and Table6.8-3(b) lists out the relations of typical noise specification, Gain, Output rate, and maximum input voltage of single end. Test condition configuration and external input signal short, voltage reference: 1.2V and 1024 records were sampled.

<b>ENOB(RMS) with OSR/GAIN at A/D Clock=250Khz, VDDA=2.4V, VREF=1.2V</b>													
Max. Vin(mV) =0.9*VREF <sup>(1)</sup>	OSR				256	512	1024	2048	4096	8192	16384	32768	
	Output rate(HZ)				977	488	244	122	61	31	15	8	
	Gain	=	PGA	x	ADGN								
$\pm 2400$	0.25	=	1	x	0.25	16.14	17.41	18.04	18.47	18.80	19.06	19.23	19.31
$\pm 2160$	0.5	=	1	x	0.5	16.15	17.41	18.03	18.42	18.75	19.13	19.24	19.30
$\pm 1080$	1	=	1	x	1	16.12	17.35	17.98	18.37	18.74	19.02	19.24	19.34
$\pm 540$	2	=	1	x	2	16.06	17.18	17.80	18.20	18.64	18.98	19.17	19.32
$\pm 270$	4	=	1	x	4	15.97	16.97	17.57	17.98	18.44	18.79	19.05	19.20
$\pm 135$	8	=	1	x	8	15.79	16.66	17.20	17.70	18.16	18.50	18.85	19.10
$\pm 68$	16	=	1	x	16	15.53	16.30	16.79	17.36	17.79	18.26	18.60	18.87
$\pm 8$	128	=	8	x	16	13.84	14.35	14.87	15.33	15.85	16.38	16.85	17.28

(1) Max.Vin (mV) is the max. input voltage of single end to ground (VSS).

Table6.8-3(a) SD18 ENOB Table

<b>RMS Noise(uV) with OSR/GAIN at A/D Clock=250Khz, VDDA=2.4V, VREF=1.2V</b>													
Max. Vin(mV) =0.9*VREF	OSR				256	512	1024	2048	4096	8192	16384	32768	
	Output rate(HZ)				977	488	244	122	61	31	15	8	
	Gain	=	PGA	x	ADGN								
$\pm 2400$	0.25	=	1	x	0.25	133.39	55.79	35.80	26.52	21.22	17.56	15.68	14.77
$\pm 2160$	0.5	=	1	x	0.5	66.41	27.72	18.10	13.82	11.01	8.37	7.75	7.45
$\pm 1080$	1	=	1	x	1	33.93	14.45	9.32	7.11	5.51	4.53	3.88	3.62
$\pm 540$	2	=	1	x	2	17.68	8.15	5.28	4.00	2.96	2.32	2.04	1.84
$\pm 270$	4	=	1	x	4	9.42	4.69	3.10	2.34	1.69	1.32	1.11	1.00
$\pm 135$	8	=	1	x	8	5.33	2.91	2.00	1.41	1.03	0.81	0.64	0.54
$\pm 68$	16	=	1	x	16	3.17	1.87	1.33	0.90	0.66	0.48	0.38	0.31
$\pm 8$	128	=	8	x	16	1.28	0.90	0.63	0.46	0.32	0.22	0.16	0.12

Table6.8-3(b) SD18 RMS Noise Table



The RMS noise are referred to the input. The Effective Number of Bits (ENOB(RMS Bit)) is defined as:

$$\text{ENOB(RMS)} = \frac{\ln\left(\frac{\text{FSR}}{\text{RMS Noise}}\right)}{\ln(2)}$$

$$\text{RMS Noise} = \frac{\left(2 \times \text{VREF} \times \sqrt{\sum_{k=1}^{1024} (\text{ADO}[k] - \text{Average})^2}\right)}{2^{23}}$$

Where FSR (Full- Scale Range) =  $2 \times \text{VREF}/\text{Gain}$ .

$$\text{Average} = \frac{\sum_{k=1}^{1024} (\text{ADO}[k])}{1024}$$

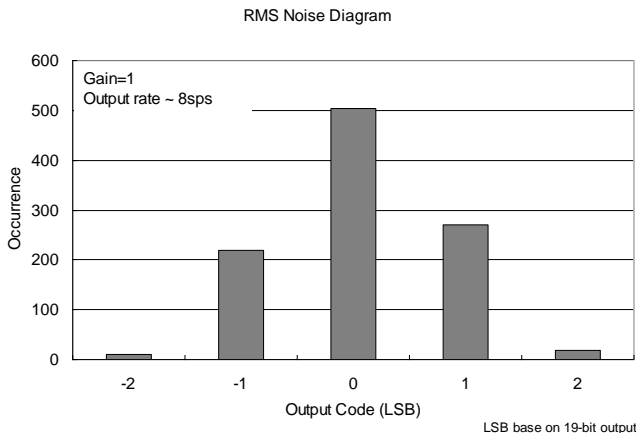


Figure 6.8-3(a) RMS Noise Diagram

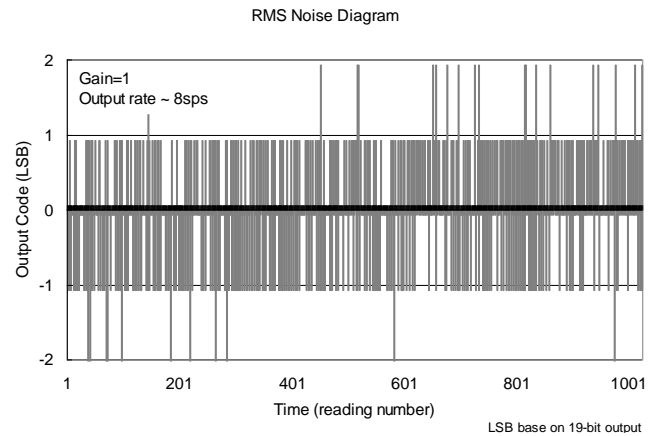


Figure 6.8-3(b) Output Code Diagram

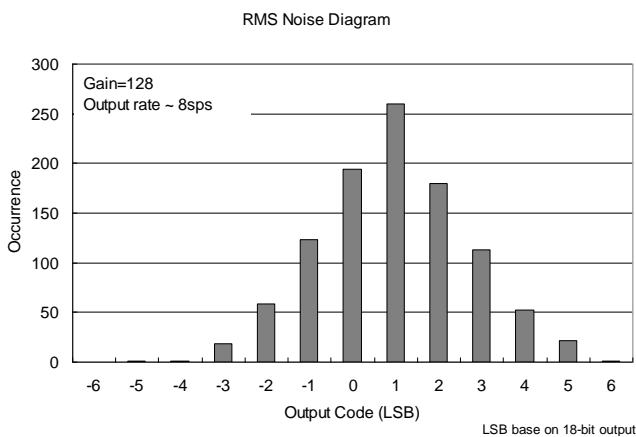


Figure 6.8-3(c) RMS Noise Diagram

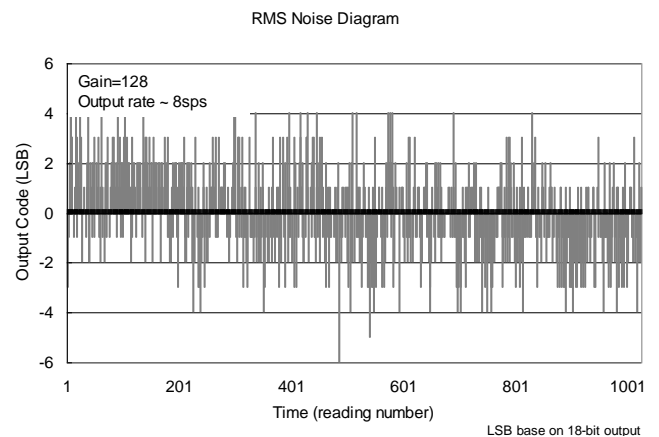


Figure 6.8-3(d) Output Code Diagram

## 6.9 Built-in EPROM (BIE)

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}$ , unless otherwise noted

Sym.	Parameter	Test Conditions	Min.	Typ.	Max.	unit
$V_{BIE}$	Supply Voltage			6.0	6.5	V
$I_{BIE}$	Operation supply current			5		mA
$V_{SS}$	Supply Voltage			0		V

## 7. Ordering Information

Device No. <sup>1</sup>	Package Type	Pins	Package Drawing		Code <sup>2</sup>	Shipment Packing Type	Unit Q'ty	Material Composition	MSL <sup>3</sup>
HY11P32-D000	Die	-	D	000	000	-	250	Green <sup>4</sup>	-
HY11P32-L044	LQFP	44	L	044	000	Tray	160	Green <sup>4</sup>	MSL-3
HY11P32-L048	LQFP	48	L	048	000	Tray	250	Green <sup>4</sup>	MSL-3

<sup>1</sup> **Device No.:** Model No. – Package Type Description – Code (Blank Code/ Standard/ Customized Programming Code)

Ex: Your customized programming code is 008 and you require die shipment.

The device No. will be HY11P32-D000-008.

Ex: You request blank code in die package.

The device No. will be HY11P32-D000.

Ex: You request blank code in LQFP 44 package.

The device No. will be HY11P32-L044.

And please clearly indicate the shipment packing type when placing orders.

Ex: Your customized programming code is 009 and you require products in LQFP 48 package.

The device No. will be HY11P32-L048-009.

And please clearly indicate the shipment packing type when placing orders.

<sup>2</sup> **Code:**

“001”~ “999” is standard or customized programming code. Blank code does not have these numbers.

<sup>3</sup> **MSL:**

The Moisture Sensitivity Level ranking conforms to IPC/JEDEC J-STD-020 industry standard categorization. The products are processed, packed, transported and used with reference to IPC/JEDEC J-STD-033.

<sup>4</sup> **Green (RoHS & no Cl/Br):**

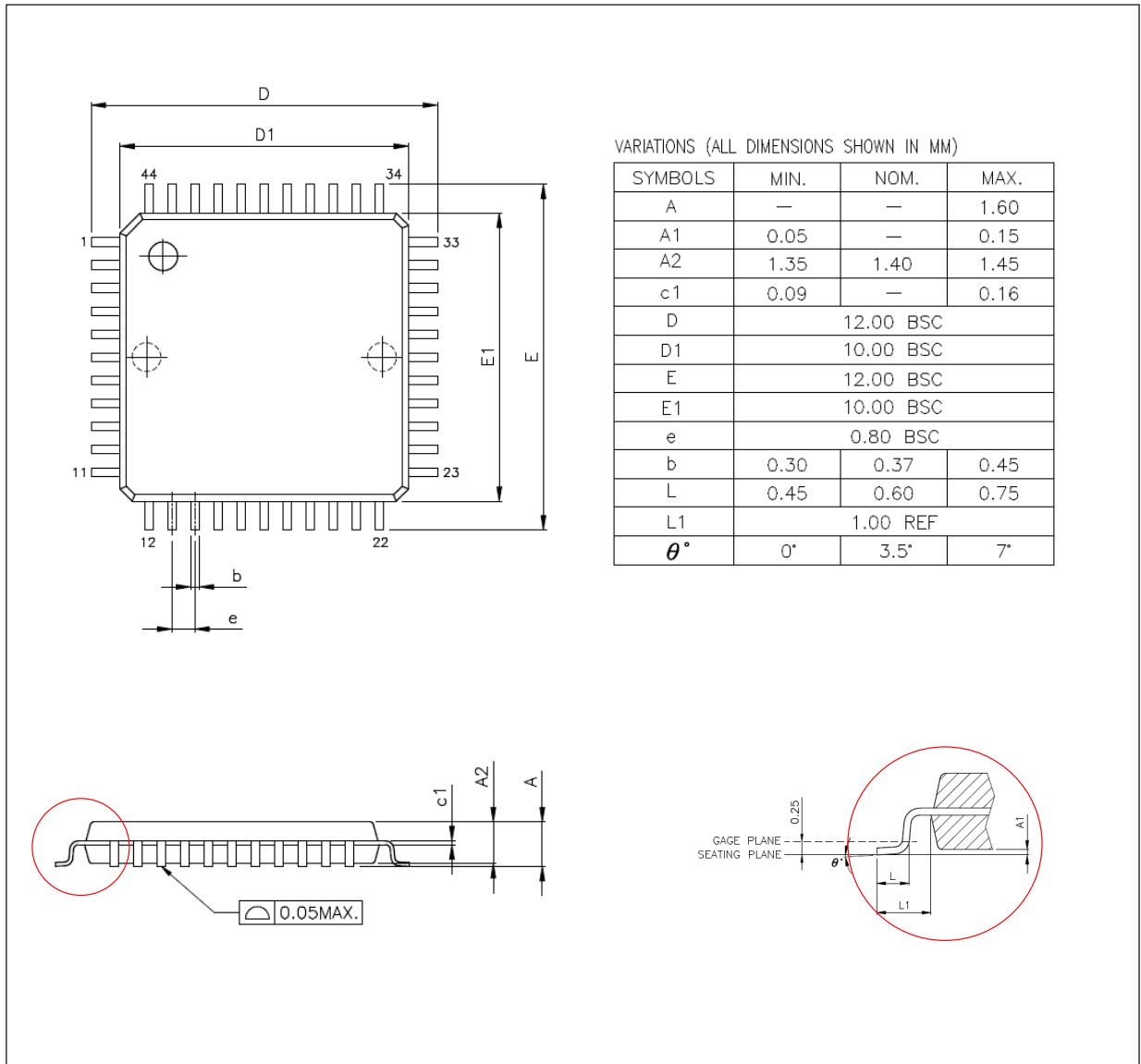
HYCON products are Green products that compliant with RoHS directive and are Halogen free (Br/Cl<0.1%)

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8-Bit RISC-Like Mixed Signal Microcontroller

## 8. Package Information

### 8.1 LQFP44(L044)

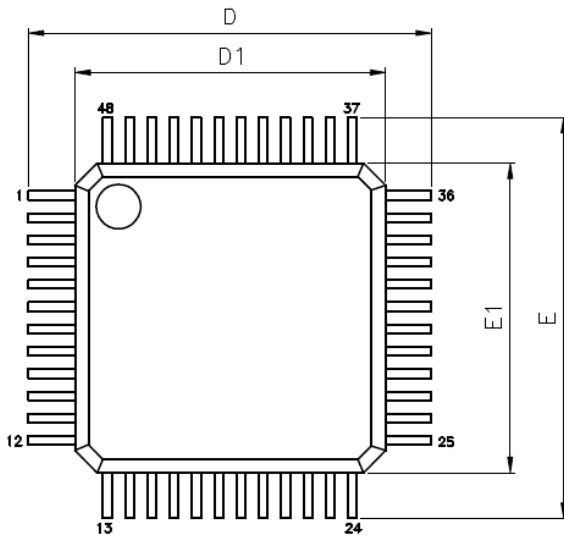


JEDEC MS-026 compliant

# HY11P32

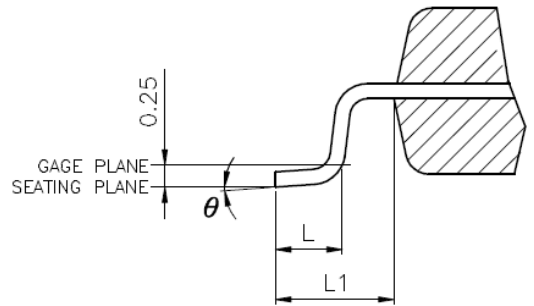
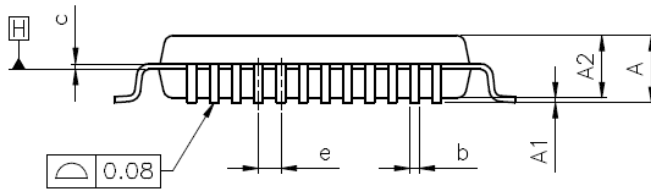
Embedded 18-Bit  $\Sigma\Delta$ ADC  
8-Bit RISC-Like Mixed Signal Microcontroller

## 8.2 LQFP48(L048)



VARIATIONS (ALL DIMENSIONS SHOWN IN MM)

SYMBOLS	MIN.	NOM.	MAX.
A	--	--	1.60
A1	0.05	--	0.15
A2	1.35	1.40	1.45
b	0.17	0.22	0.27
c	0.09	--	0.20
D	9.00 BSC		
D1	7.00 BSC		
E	9.00 BSC		
E1	7.00 BSC		
e	0.50 BSC		
L	0.45	0.60	0.75
L1	1.00 REF		
$\theta$	0°	3.5°	7°



JEDEC MS-026 compliant

## 9. Revision Record

Major differences are stated thereafter:

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Version	Page	Revision Summary
V03	ALL	First edition
V08	1	Title Revised
	6	Add in LVDIN function of PT1.2
	7	Add in LVDIN function of PT1.2
	9	Add in LVDIN function of PT1.2
	10	Revise the content of block diagram, WDT reset is 00H
	11	Add in Chapter 4.3 SD18 Network
	12	Revise register list, add in LVDIN function of PT1.2
	14	HAO spec revised, 2MHz $\pm$ 20%
	17	Add in LVDIN function of PT1.2
	23	Revise Figure 6.8 content and order
V12	5	Revise Chapter 1 Features Content
	11	Revise Figure 4.1 and 4.2 Development Tool Related Operating Instruction serial numbers
	14	Revise Chapter 6 Electrical Characteristics Content
	20	Revise Power System Temperature Drift Spec
	25~26	Add in Chapter 6.8.3 SD18 Noise Performance
	28	Chapter 7 Ordering information revision